Product data sheet

1. General description

The BGU8M1 is, also known as the LTE1001M, a Low-Noise Amplifier (LNA) for LTE receiver applications, available in a small plastic 6-pin extremely thin leadless package. The BGU8M1 requires one external matching inductor.

The BGU8M1 adapts itself to the changing environment resulting from co-habitation of different radio systems in modern cellular handsets. It has been designed for low power consumption and optimal performance. At low jamming power levels, it delivers 13 dB gain at a noise figure of 0.8 dB. During high-power levels, it temporarily increases its bias current to improve sensitivity.

The BGU8M1 is optimized for 1805 MHz to 2200 MHz.

2. Features and benefits

- Operating frequency from 1805 MHz to 2200 MHz
- Noise figure = 0.8 dB
- Gain = 13 dB
- High input 1 dB compression point of -2 dBm
- High in band IP3_i of 6 dBm
- Supply voltage 1.5 V to 3.1 V
- Self-shielding package concept
- Integrated supply decoupling capacitor
- Optimized performance at a supply current of 5 mA
- Power-down mode current consumption < 1 μA</p>
- Integrated temperature stabilized bias for easy design
- Require only one input matching inductor
- Output DC decoupled
- ESD protection on all pins (HBM > 2 kV)
- Integrated matching for the output
- Available in a6-pin leadless package 1.1 mm \times 0.7 mm \times 0.37 mm; 0.4 mm pitch: SOT1232
- 180 GHz transit frequency SiGe:C technology
- Moisture sensitivity level 1



SiGe:C low-noise amplifier MMIC for LTE

3. Applications

- LNA for LTE reception in smart phones
- Feature phones
- Tablet PCs
- RF front-end modules

4. Quick reference data

Table 1. Quick reference data

f = 1843 MHz; V_{CC} = 2.8 V; $V_{I(ENABLE)} \ge 0.8$ V; T_{amb} = 25 °C; input matched to 50 Ω using a 3.3 nH inductor; unless otherwise specified.

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|---------------------|--------------------------------------|------------|-----|------|-----|------|
| V _{CC} | supply voltage | | 1.5 | - | 3.1 | V |
| I _{CC} | supply current | | 3.0 | 5.0 | 7.0 | mA |
| Gp | power gain | [1] | - | 13.5 | - | dB |
| NF | noise figure | [1][2] | - | 0.8 | - | dB |
| P _{i(1dB)} | input power at 1 dB gain compression | [1] | - | -2 | - | dBm |
| IP3 _i | input third-order intercept point | [1] | - | 4 | - | dBm |

^[1] E-UTRA operating band 3 (1805 MHz to 1880 MHz).

5. Ordering information

Table 2. Ordering information

| Type number | Package | | | |
|-------------|---------|---|---------|--|
| | Name | Description | Version | |
| BGU8M1 | XSON6 | plastic extremely thin small outline package; no leads; 6 terminals; body 1.1 \times 0.7 \times 0.37 mm | SOT1232 | |

6. Marking

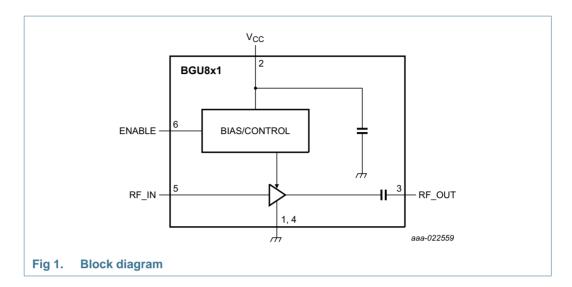
Table 3. Marking codes

| Type number | Marking code |
|-------------|--------------|
| BGU8M1 | E |

^[2] PCB losses are subtracted.

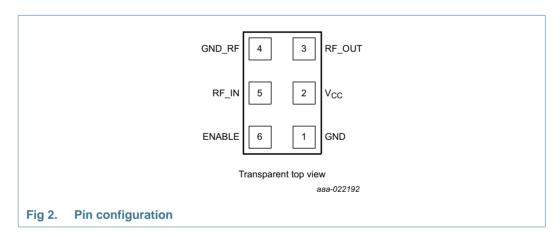
SiGe:C low-noise amplifier MMIC for LTE

7. Block diagram



8. Pinning information

8.1 Pinning



8.2 Pin description

Table 4. Pin description

| Symbol | Pin | Description |
|-----------------|-----|----------------|
| GND | 1 | ground |
| V _{CC} | 2 | supply voltage |
| RF_OUT | 3 | RF output |
| GND_RF | 4 | ground RF |
| RF_IN | 5 | RF input |
| ENABLE | 6 | enable |

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9. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Absolute maximum ratings are given as limiting values of stress conditions during operation, that must not be exceeded under the worst probable conditions.

| Symbol | Parameter | Conditions | | Min | Max | Unit |
|------------------------|---------------------------------|---|------------|------|------|------|
| V _{CC} | supply voltage | RF input AC coupled | <u>[1]</u> | -0.5 | +5.0 | V |
| V _{I(ENABLE)} | input voltage on pin ENABLE | V _{I(ENABLE)} < V _{CC} + 0.6 V | [1][2] | -0.5 | +5.0 | V |
| V _{I(RF_IN)} | input voltage on pin RF_IN | DC; V _{I(RF_IN)} < V _{CC} + 0.6 V | [1][2] | -0.5 | +5.0 | V |
| V _{I(RF_OUT)} | input voltage on pin RF_OUT | DC; V _{I(RF_OUT)} < V _{CC} + 0.6 V | [1][2][3] | -0.5 | +5.0 | V |
| Pi | input power | | <u>[1]</u> | - | 26 | dBm |
| P _{tot} | total power dissipation | $T_{sp} \le 130 ^{\circ}C$ | | - | 55 | mW |
| T _{stg} | storage temperature | | | -65 | +150 | °C |
| Tj | junction temperature | | | - | 150 | °C |
| V _{ESD} | electrostatic discharge voltage | Human Body Model (HBM) according to ANSI/ESDA/JEDEC standard JS-001 | | - | ±2 | kV |
| | | Charged Device Model (CDM) according to JEDEC standard JESD22-C101C | | - | ±1 | kV |

^[1] Stressed with pulses of 1 s in duration. V_{CC} connected to a power supply of 2.8 V with 500 mA current limit.

10. Recommended operating conditions

Table 6. Operating conditions

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|------------------------|-----------------------------|------------|-----|-----|-----|------|
| V _{CC} | supply voltage | | 1.5 | - | 3.1 | V |
| T _{amb} | ambient temperature | | -40 | +25 | +85 | °C |
| V _{I(ENABLE)} | input voltage on pin ENABLE | OFF state | - | - | 0.3 | V |
| | | ON state | 0.8 | - | - | V |

11. Thermal characteristics

Table 7. Thermal characteristics

| Symbol | Parameter | Conditions | Тур | Unit |
|----------------|--|------------|-----|------|
| $R_{th(j-sp)}$ | thermal resistance from junction to solder point | | 225 | K/W |

^[2] Warning: Due to internal ESD diode protection, to avoid excess current, the applied DC voltage must not exceed V_{CC} + 0.6 V or 5.0 V.

^[3] The RF output is AC coupled through internal DC blocking capacitors.

SiGe:C low-noise amplifier MMIC for LTE

12. Characteristics

Table 8. Characteristics at $V_{CC} = 1.8 \text{ V}$

1805 MHz \leq f \leq 2200 MHz; V_{CC} = 1.8 V; $V_{I(ENABLE)} \geq$ 0.8 V; T_{amb} = 25 °C; input matched to 50 Ω using a 3.3 nH inductor; unless otherwise specified.

| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
|---------------------|-----------------------------------|--|-----------|------|------|------|------|
| I _{CC} | supply current | V _{I(ENABLE)} ≥ 0.8 V | | 2.7 | 4.7 | 6.7 | mA |
| | | $V_{I(ENABLE)} \le 0.3 \text{ V}$ | | - | - | 1 | μΑ |
| Gp | power gain | f = 1843 MHz | [1] | - | 13.5 | - | dB |
| | | f = 1960 MHz | [2] | 11.0 | 13.0 | 15.0 | dB |
| | | f = 2140 MHz | [3] | - | 12.5 | - | dB |
| RLin | input return loss | f = 1843 MHz | [1] | - | 7 | - | dB |
| | | f = 1960 MHz | [2] | - | 8 | - | dB |
| | | f = 2140 MHz | [3] | - | 8 | - | dB |
| RLout | output return loss | f = 1843 MHz | [1] | - | 20 | - | dB |
| | | f = 1960 MHz | [2] | - | 20 | - | dB |
| | | f = 2140 MHz | [3] | - | 18 | - | dB |
| ISL | isolation | f = 1843 MHz | [1] | - | 20 | - | dB |
| | | f = 1960 MHz | [2] | - | 20 | - | dB |
| | | f = 2140 MHz | [3] | - | 20 | - | dB |
| NF | noise figure | f = 1843 MHz | [1][4] | - | 0.8 | - | dB |
| | | f = 1960 MHz | [2][4][5] | - | 0.8 | 1.4 | dB |
| | | f = 2140 MHz | [3][4] | - | 0.9 | - | dB |
| P _{i(1dB)} | input power at 1 dB | f = 1843 MHz | [1] | - | -8 | - | dBm |
| | gain compression | f = 1960 MHz | [2][5] | -12 | -8 | - | dBm |
| | | f = 2140 MHz | [3] | - | -7 | - | dBm |
| IP3 _i | input third-order intercept point | f = 1843 MHz | [1] | - | 0 | - | dBm |
| | | f = 1960 MHz | [2][5] | -4 | +1 | - | dBm |
| | | f = 2140 MHz | [3] | - | 2 | - | dBm |
| K | Rollett stability factor | | | 1 | - | - | - |
| t _{on} | turn-on time | time from V _{I(ENABLE)} ON to 90 % of the gain | | - | - | 4 | μS |
| t _{off} | turn-off time | time from V _{I(ENABLE)} OFF to 10 % of the gain | | - | - | 1 | μS |
| | 1 | <u> </u> | | | | | |

^[1] E-UTRA operating band 3 (1805 MHz to 1880 MHz).

^[2] E-UTRA operating band 2 (1930 MHz to 1990 MHz).

^[3] E-UTRA operating band 1 (2110 MHz to 2170 MHz).

^[4] PCB losses are subtracted.

^[5] Guaranteed by device design; not tested in production.

SiGe:C low-noise amplifier MMIC for LTE

Table 9. Characteristics at $V_{CC} = 2.8 \text{ V}$

1805 MHz \leq f \leq 2200 MHz; V_{CC} = 2.8 V; $V_{I(ENABLE)} \geq$ 0.8 V; T_{amb} = 25 °C; input matched to 50 Ω using a 3.3 nH inductor; unless otherwise specified.

| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
|---------------------|-----------------------------------|--|-----------|------|------|------|------|
| I _{CC} | supply current | V _{I(ENABLE)} ≥ 0.8 V | | 3.0 | 5.0 | 7.0 | mA |
| | | $V_{I(ENABLE)} \le 0.3 \text{ V}$ | | - | - | 1 | μΑ |
| Gp | power gain | f = 1843 MHz | [1] | - | 13.5 | - | dB |
| | | f = 1960 MHz | [2] | 11.5 | 13.5 | 15.5 | dB |
| | | f = 2140 MHz | [3] | - | 13 | - | dB |
| RLin | input return loss | f = 1843 MHz | [1] | - | 8 | - | dB |
| | | f = 1960 MHz | [2] | - | 8 | - | dB |
| | | f = 2140 MHz | [3] | - | 9 | - | dB |
| RL _{out} | output return loss | f = 1843 MHz | [1] | - | 20 | - | dB |
| | | f = 1960 MHz | [2] | - | 20 | - | dB |
| | | f = 2140 MHz | [3] | - | 20 | - | dB |
| ISL isolation | isolation | f = 1843 MHz | [1] | - | 20 | - | dB |
| | | f = 1960 MHz | [2] | - | 20 | - | dB |
| | | f = 2140 MHz | [3] | - | 20 | - | dB |
| NF | noise figure | f = 1843 MHz | [1][4] | - | 0.8 | - | dB |
| | | f = 1960 MHz | [2][4][5] | - | 0.8 | 1.4 | dB |
| | | f = 2140 MHz | [3][4] | - | 0.9 | - | dB |
| P _{i(1dB)} | input power at 1 dB | f = 1843 MHz | [1] | - | -2 | - | dBm |
| | gain compression | f = 1960 MHz | [2][5] | -6 | -2 | - | dBm |
| | | f = 2140 MHz | [3] | - | -2 | - | dBm |
| IP3 _i | input third-order intercept point | f = 1843 MHz | [1] | - | 4 | - | dBm |
| | | f = 1960 MHz | [2][5] | 0 | 5 | - | dBm |
| | | f = 2140 MHz | [3] | - | 6 | - | dBm |
| K | Rollett stability factor | | | 1 | - | - | - |
| t _{on} | turn-on time | time from V _{I(ENABLE)} ON to 90 % of the gain | | - | - | 4 | μS |
| t _{off} | turn-off time | time from V _{I(ENABLE)} OFF to 10 % of the gain | | - | - | 1 | μS |
| | , , | | | | | _ | |

^[1] E-UTRA operating band 3 (1805 MHz to 1880 MHz).

^[2] E-UTRA operating band 2 (1930 MHz to 1990 MHz).

^[3] E-UTRA operating band 1 (2110 MHz to 2170 MHz).

^[4] PCB losses are subtracted.

^[5] Guaranteed by device design; not tested in production.

13. Package outline

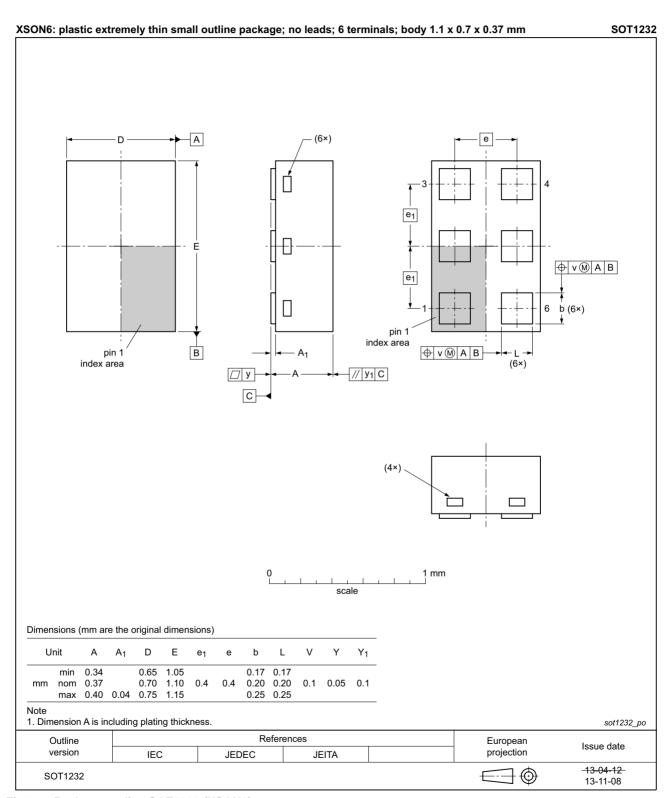


Fig 3. Package outline SOT1232 (XSON6)

SiGe:C low-noise amplifier MMIC for LTE

14. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

15. Abbreviations

Table 10. Abbreviations

| Acronym | Description |
|---------|---|
| ESD | ElectroStatic Discharge |
| E-UTRA | Evolved UMTS Terrestrial Radio Access |
| НВМ | Human Body Model |
| LNA | Low-Noise Amplifier |
| LTE | Long Term Evolution |
| MMIC | Monolithic Microwave Integrated Circuit |
| PCB | Printed-Circuit Board |
| SiGe:C | Silicon Germanium Carbon |

16. Revision history

Table 11. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes | | |
|----------------|-----------------------|--------------------------|---------------------------------|------------|--|--|
| BGU8M1 v.3 | 20170116 | Product data sheet | | BGU8M1 v.2 | | |
| Modifications: | Section 1: a | added LTE1001M according | ng to our new naming convention | | | |
| BGU8M1 v.2 | 20160404 | Product data sheet | - | BGU8M1 v.1 | | |
| Modifications: | • <u>Table 5</u> : up | dated input power | | • | | |
| | • Table 8: up | dated | | | | |
| | • <u>Table 9</u> : up | dated | | | | |
| BGU8M1 v.1 | 20140603 | Product data sheet | - | - | | |

SiGe:C low-noise amplifier MMIC for LTE

17. Legal information

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| Document status[1][2] | Product status[3] | Definition |
|--------------------------------|-------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

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- [2] The term 'short data sheet' is explained in section "Definitions"
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BGU8M1

SiGe:C low-noise amplifier MMIC for LTE

19. Contents

| 1 | General description | 1 |
|------|----------------------------------|----|
| 2 | Features and benefits | 1 |
| 3 | Applications | 2 |
| 4 | Quick reference data | 2 |
| 5 | Ordering information | 2 |
| 6 | Marking | 2 |
| 7 | Block diagram | 3 |
| 8 | Pinning information | 3 |
| 8.1 | Pinning | 3 |
| 8.2 | Pin description | 3 |
| 9 | Limiting values | 4 |
| 10 | Recommended operating conditions | 4 |
| 11 | Thermal characteristics | 4 |
| 12 | Characteristics | 5 |
| 13 | Package outline | 7 |
| 14 | Handling information | 8 |
| 15 | Abbreviations | 8 |
| 16 | Revision history | 8 |
| 17 | Legal information | 9 |
| 17.1 | Data sheet status | |
| 17.2 | Definitions | |
| 17.3 | Disclaimers | |
| 17.4 | Trademarks | |
| 18 | Contact information | |
| 19 | Contents | 11 |

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